

# FAULT TOLERANT SYSTEMS

## **In Praise of Fault Tolerant Systems**

“Fault attacks have recently become a serious concern in the smart card industry. “Fault Tolerant Systems” provides the reader with a clear exposition of these attacks and the protection strategies that can be used to thwart them. A must read for practitioners and researchers working in the field.”

David Naccache, Ecole normale supérieure

“Understanding the fundamentals of an area, whether it is golf or fault tolerance, is a prerequisite to developing expertise in the area. Krishna and Koren’s book can provide a reader with this underlying foundation for fault tolerance. This book is particularly timely because the design of fault-tolerant computing components, such as processors and disks, is becoming increasingly important to the mainstream computing industry.”

Shubu Mukherjee, Director, FACT-AMI Group, Intel Corporation

“Professors Koren and Krishna, have written a modern, dual purpose text that first presents the basics fault tolerance tools describing various redundancy types both at the hardware and software levels followed by current research topics. It reviews fundamental reliability modeling approaches, combinatorial blocks and Markov chain techniques. Notably, there is a complete chapter on statistical simulation methods that offers guidance to practical evaluations as well as one on fault-tolerant networks. All chapters, which are clearly written including illuminating examples, have extensive reference lists whereby students can delve deeper into almost any topic. Several practical and commercial computing systems that incorporate fault tolerance are detailed. Furthermore, there are two chapters introducing current fault tolerance research challenges, cryptographic systems and defects in VLSI designs.”

Robert Redinbo, UC Davis

“The field of Fault-Tolerant Computing has advanced considerably in the past ten years and yet no effort has been made to put together these advances in the form of a book or a comprehensive paper for the students starting in this area. This is the first book I know of in the past 10 years that deals with hardware and software aspects of fault tolerant computing, is very comprehensive, and is written as a text for the course.”

Kewal Saluja, University of Wisconsin, Madison

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**Israel Koren**

**C. Mani Krishna**



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# Foreword

Systems used in critical applications such as health, commerce, transportation, utilities, and national security must be highly reliable. Ubiquitous use of computing systems and other electronic systems in these critical areas requires that computing systems have high reliability. High reliability is achieved by designing the systems to be fault-tolerant. Even though the high reliability requirements of computing systems gave the original impetus to the study of the design of fault-tolerant systems, trends in manufacturing of VLSI circuits and systems are also requiring the use of fault-tolerant design methods to achieve high yields from manufacturing plants. This is due to the fact that with reduced feature sizes of VLSI circuit designs and shortcomings of lithographic techniques used in fabrication the characteristics of the manufactured devices are becoming unpredictable. Additionally small sizes of devices make them susceptible to radiation induced failures causing run time errors. Thus it may be necessary to use fault tolerance techniques even in systems that are used in non-critical applications such as consumer electronics.

This book covers comprehensively the design of fault-tolerant hardware and software, use of fault-tolerance techniques to improve manufacturing yields and design and analysis of networks. Additionally it includes material on methods to protect against threats to encryption subsystems used for security purposes. The material in the book will help immensely students and practitioners in electrical and computer engineering and computer science in learning how to design reliable computing systems and how to analyze fault-tolerant computing systems.

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# Preface

The purpose of this book is to provide a solid introduction to the rich field of fault-tolerant computing. Its intended use is as a text for senior-level undergraduate and first-year graduate students, as well as a reference for practicing engineers in the industry. Since it would be impossible to cover in one book all the fault-tolerance techniques and practices that have been developed or are currently in use, we have focused on providing the basics of the field and enough background to allow the reader to access more easily the rapidly expanding fault-tolerance literature. Readers who are interested in further details should consult the list of references at the end of each chapter. To understand this book well, the reader should have a basic knowledge of hardware design and organization, principles of software development, and probability theory.

The book has 10 chapters; each chapter has a list of relevant references and a set of exercises. Solutions to the exercises are available on-line and access to them is provided by the publisher upon request to instructors who adopt this book as a textbook for their class. Powerpoint slides for instructors are also available.

The book starts with an outline of preliminaries, in which we provide introductory information. This is followed by a set of six chapters that form the core of what we believe should be covered in any introduction to fault-tolerant systems.

Chapter 2 deals with hardware fault-tolerance; this is the discipline with the longest history (indeed, the idea of using hardware redundancy for fault-tolerance goes back to the very pioneers of computing, most notably von Neumann). We also include in this chapter an introduction to some of the probabilistic tools used in analyzing reliability measures.

Chapter 3 deals with information redundancy with the main focus on error detecting and correcting codes. Such codes, like hardware fault-tolerance, go back a very long way, and were motivated in large measure by the need to counter errors in information transmission. The same, or similar, techniques are being used today in other applications as well, principally in contemporary memory circuits. We have sought to provide a survey of only the more important coding techniques,

and it was not intended to be comprehensive: indeed, a comprehensive survey of coding would require multiple volumes. Following this, we turn to the issue of managing information redundancy in storage, and end with algorithm-based fault-tolerance.

Chapter 4 covers fault-tolerant networks. With processors becoming cheaper, distributed systems are becoming more commonplace; we look at some key network topologies and consider how to quantify and enhance their fault-tolerance.

Chapter 5 describes techniques for software fault-tolerance. It is widely believed that software accounts for a majority of the failures seen in today's computer systems. As a field, software fault-tolerance is less mature than fault-tolerance using either hardware or information redundancy. It is also a much harder nut to crack. Software is probably the most complex artificial construct that people have created, and rendering it fault-tolerant is an arduous task. We cover such techniques as recovery blocks and N-version programming, together with a discussion of acceptance tests and ways to model software failure processes analytically.

In Chapter 6, we cover the use of time-redundancy through checkpointing. The majority of hardware failures are transient in nature; in other words, they are failures which simply go away after some time. An obvious response to such failures is to roll back the execution and re-execute the program. Checkpointing is a technique which allows us to limit the extent of such re-executions.

Chapter 7, which contains several case studies, rounds off the core of the book. There, we describe several real-life examples of fault-tolerant systems illustrating the usage of the various techniques presented in the previous chapters.

The remaining three chapters of the book deal with more specialized topics. In Chapter 8, we cover defect-tolerance in VLSI. As die sizes increase and feature sizes drop, it is becoming increasingly important to be able to tolerate manufacturing defects in a VLSI chip without affecting its functionality. We discuss the key approaches being used, as well as the underlying mathematical models.

In Chapter 9, we focus on cryptographic devices. The increasing use of computers in commerce, including smart cards and Internet shopping, has motivated the use of encryption in everyday applications. It turns out that injecting faults into cryptographic devices and observing the outputs is an effective way to attack secure systems and obtain their secret key. We present in this chapter the use of fault-detection to counter these types of security attacks.

Chapter 10, which ends the book, deals with simulation and experimental techniques. Simulating a fault-tolerant system to measure its reliability is often computationally very demanding. We provide in this chapter an outline of basic simulation techniques, as well as ways in which simulation can be accelerated. Also provided are basic statistical tools by which simulation output can be analyzed and an outline of experimental fault-injection techniques.

A companion web site ([www.ecs.umass.edu/ece/koren/FaultTolerantSystems/](http://www.ecs.umass.edu/ece/koren/FaultTolerantSystems/)) includes additional resources for the book such as lecture slides, the inevitable list of errors, and, more importantly, a link to an extensive collection of

educational tools and simulators that can be of great assistance to the readers of the book. Elsevier also maintains an instructor web site that will house the solutions for those who adopt this book as a textbook for their class. The website can be found at <http://textbooks.elsevier.com>.





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